

# Takano WM-10

## Particle Measurement System

The advanced solution for particle measurement on  $\leq 300\text{mm}$  unpatterned wafers

### System Overview

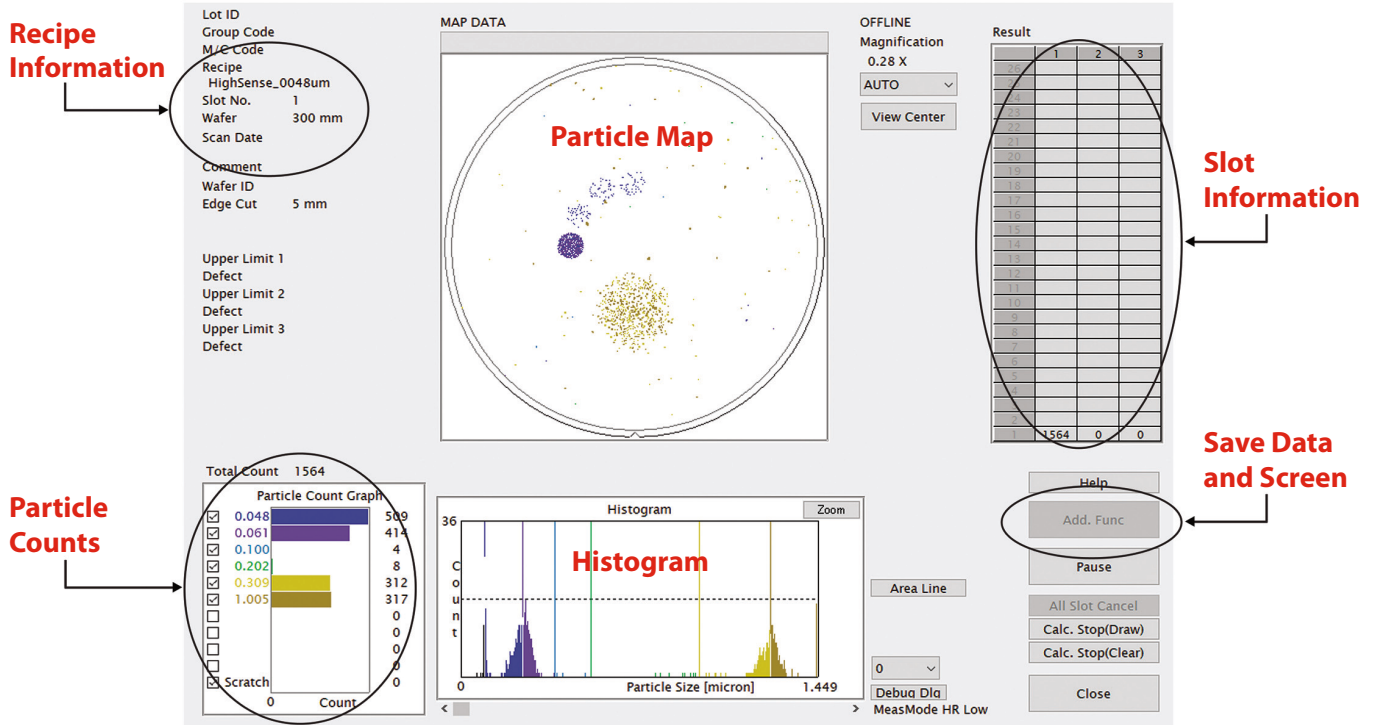
The Takano WM-10 offers high-sensitivity particle measurements on non-patterned  $\leq 300\text{mm}$  wafers. Capable of measuring bare or filmed wafers, the WM-10 system can deliver reliable 48nm detection sensitivity along with high throughput and excellent repeatability. The Takano WM-10 is a modern and cost-effective particle measurement solution – for today's requirements and for the future.



### Key Features & Benefits

- Advanced performance and superior cost-effectiveness
- 48nm particle detection sensitivity
- Dual laser angle (Optional)
- 70 WPH throughput
- Windows 10 operating system
- Long-life 405nm laser diode
- Single or dual FOUP, or open-cassette handler
- Full suite of options: Map Overlay, Haze Measurements, XY Coordinate Output, and much more
- Extensive OEM parts and service support, available long-term
- Quality-manufactured in Japan

## Measurement Results



## Measurement Specifications

- Maximum detection sensitivity: 0.048 $\mu$ m
- Dynamic range: 0.048 – 5 $\mu$ m
- Reproducibility of detection:  $\leq$ 1%
- Throughput: 70 WPH on 300mm wafers

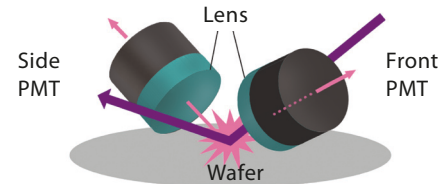
## Software/Hardware Options

- Dual-incident angle laser
- Map overlay function
- X-Y coordinate output
- Auto-sensitivity correction
- Haze measurement
- GEM300 communication
- Remote desktop
- ULPA-equipped Fan Filter Unit (FFU)
- Signal light tower
- Bare and filmed PSL calibration wafers

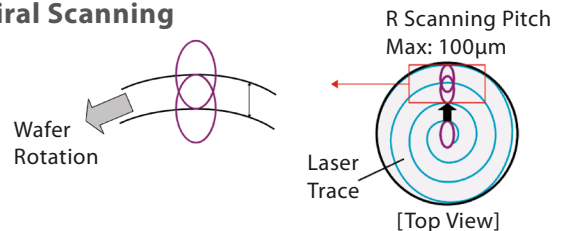
## Hardware Specifications

- Single or dual FOUP or open-cassette handler
- 405nm violet laser diode
- Windows 10 operating system
- 15" LCD monitor

## Low-Angle Incident Polarization, P or S



## Spiral Scanning



## High Incident Angle Option

